



Product Change Notification / ASER-13KWIQ013

Date:

15-Dec-2021

Product Category:

32-bit Microcontrollers

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4978 Initial Notice: Qualification of MMT as an additional assembly site for selected ATSAME5xxx and ATSAMD5xxx device families available in 128L TQFP (14x14x1mm) package.

Affected CPNs:

[ASER-13KWIQ013_Affected_CPN_12152021.pdf](#)
[ASER-13KWIQ013_Affected_CPN_12152021.csv](#)

Notification Text:

PCN Status:Initial Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.
Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of MMT as an additional assembly site for selected ATSAME5xxx and ATSAMD5xxx device families available in 128L TQFP (14x14x1mm) package.

Pre and Post Change Summary:

	Pre Change	Post Change

Method to Identify Change:Traceability code

Qualification Plan:Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History:December 15, 2021: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_ASER-13KWIQ0131_Pre and Post Change Summary.pdf](#)

[PCN_ASER-13KWIQ013 Qual Plan.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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QUALIFICATION PLAN SUMMARY

PCN #: ASER-13KWIQ013

**Date:
December 09, 2021**

Qualification of MMT as an additional assembly site for selected ATSAME5xxx and ATSAMD5xxx device families available in 128L TQFP (14x14x1mm) package.

Purpose: Qualification of MMT as an additional assembly site for selected ATSAME5xxx and ATSAMD5xxx device families available in 128L TQFP (14x14x1mm) package.

CCB: 4978

<u>Misc.</u>	Assembly site	MMT
	BD Number	BD-000266 rev02
	MP Code (MPC)	65106YZ2XC01
	Part Number (CPN)	ATSAME54P20A-AFT
<u>Lead-Frame</u>	Paddle size	190x190 mils
	Material	C7025
	Surface	Double Ag Ring Plated
	Treatment	None
	Process	Stamped
	Lead-lock	No
	Part Number	10112804
	Lead Plating	Matte Tin
	Strip Size	70x250mm
	Strip Density	30 units/strip
<u>Bond Wire</u>	Material	CuPdAu
<u>Die Attach</u>	Part Number	3280
	Conductive	Yes
<u>MC</u>	Part Number	G700HA
<u>PKG</u>	PKG Type	TQFP
	Pin/Ball Count	128
	PKG width/size	14x14x1mm

Test Name	Conditions	Reliability Stress Read Point Grade 1: -40°C to +125°C (MCHP E Temp)	Pre & Post Reliability Stress Test Temperature Grade 1: -40°C to +125°C (MCHP E Temp)	Sample Size	Min. Qty of Spares per Lot <small>(should be entered manually)</small>		Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
						Qty of Lots				
Standard Pb-free Solderability	J-STD-002D ; Perform 8 hours of steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing. Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.			22	5	1	27	>95% lead coverage	5	Standard Pb-free solderability is the requirement.
Wire Bond Pull - WBP	Mil. Std. 883-2011			5	0	1	5	0	5	30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001			5	0	1	5	0	5	30 bonds from a min. 5 devices.
Physical Dimensions	Measure per JESD22 B100 and B108			10	0	3	30	0	5	
External Visual	Mil. Std. 883-2009/2010			All devices prior to submission for qualification testing	0	3	ALL	0	5	
HTSL (High Temp Storage Life)	JESD22-A103 +175°C 2x Stress	<u>1st Readpoint:</u> Grade 1: 500 hrs (+175°C) <u>2nd Readpoint:</u> Grade 1: 1000 hrs (+175°C)	Grade 1: +25°C, +125°C	45	5	3	150	0	21 - 167	Perform per the requirements in AEC-Q100/Q101. Spares should be properly identified.
Preconditioning - Required for surface mount devices	J-STD-020 JESD22-A113 +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020E for package type. MSL-3/260C		Grade 1: +25°C	231	15	3	738	0	15	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.
HAST	JESD22-A101 or A110 +130°C/85% RH for 96 hrs 2x Stress	<u>1st Readpoint:</u> Grade 1: 96 hrs (+130°C/85% RH) <u>2nd Readpoint:</u> Grade 1: 192 hrs (+130°C/85% RH)	Grade 1: +25°C, +125°C	77	5	3	246	0	10 - 22	Perform per the requirements in AEC-Q006. Spares should be properly identified. Use the parts which have gone through Pre-conditioning.

uHAST	JESD22-A102, A118, or A101 +130°C/85% RH for 96 hrs	Grade 0: 96 hrs (+130°C/85% RH) Grade 1: 96 hrs (+130°C/85% RH)	Grade 1: +25°C	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	JESD22-A104 and Appendix 3 -65°C to +150°C <i>2x Stress</i>	<u>1st Readpoint:</u> Grade 1: 500 cycles (-65°C to 150°C) <u>2nd Readpoint:</u> Grade 1 1000 cycles (-65°C to 150°C)	Grade 1: +125°C	77	5	3	246	0	15 - 120	Perform per the requirements in AEC-Q006. Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Wire Bond Integrity (AEC-Q006 Requirements)	AEC-Q006									Wire pull / ball shear is performed after stress testing and decapsulation.
Cross Sectioning (AEC-Q006 Requirements)	IPC-TM-650, Methods 2.1.1 and 2.1.1.2			1	0	3	3		5	

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Pre and Post Change Summary
PCN #: ASER-13KWIQ013



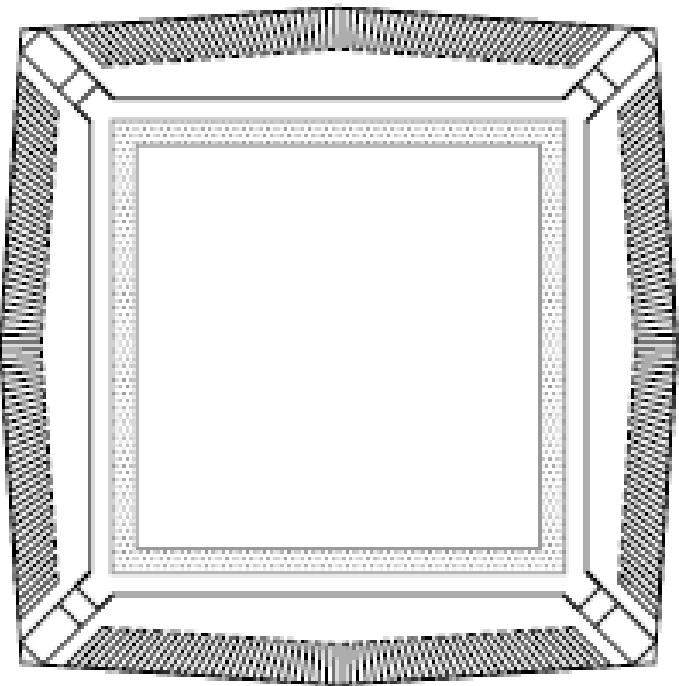
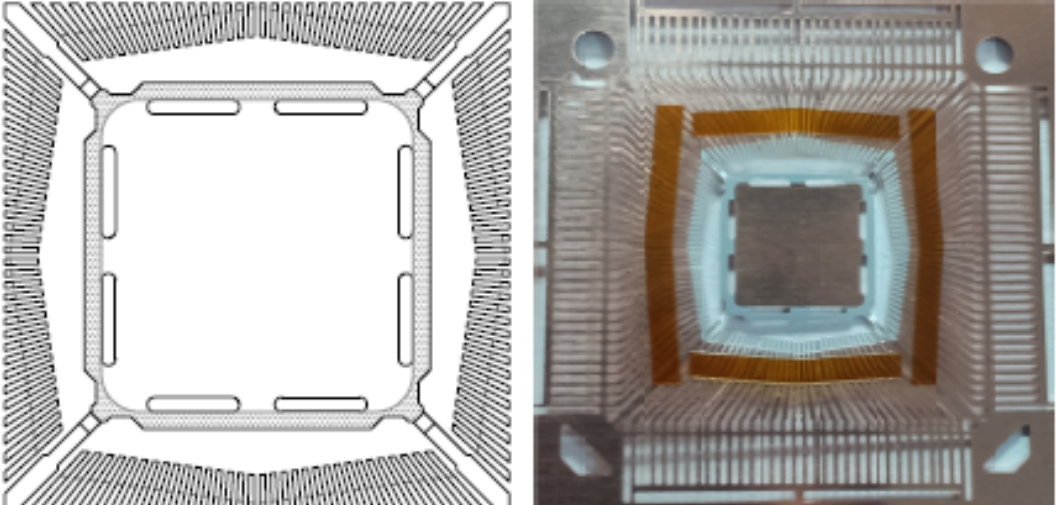
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**Qualification of MMT as an additional assembly site for selected
ATSAME5xxx and ATSAM5xxx device families available in 128L
TQFP (14x14x1mm) package.**



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Lead Frame Design Comparison

ASE	MMT				
 <p>A detailed technical drawing of an ASE lead frame. It features a square central cavity surrounded by a thick, multi-layered frame. The frame has a complex, textured appearance with various internal patterns and a slightly irregular, hand-drawn style.</p> <table border="1" data-bbox="484 1153 1026 1239"><tr><td>Paddle Size</td><td>240x240 mils</td></tr></table>	Paddle Size	240x240 mils	 <p>Two images of an MMT lead frame. On the left is a technical drawing showing a square central cavity with a more uniform, grid-like frame structure. On the right is a photograph of the physical lead frame, showing its metallic, perforated appearance and the central cavity.</p> <table border="1" data-bbox="1574 1153 2117 1239"><tr><td>Paddle Size</td><td>190x190 mils</td></tr></table>	Paddle Size	190x190 mils
Paddle Size	240x240 mils				
Paddle Size	190x190 mils				

Affected Catalog Part Numbers (CPN)

ATSAME54P20A-AF
ATSAME54P19A-AF
ATSAMD51P19A-AF
ATSAMD51P20A-AF
ATSAME54P19A-AZ
ATSAME54P20A-AZ
ATSAMD51P19A-AZ
ATSAMD51P20A-AZ
ATSAME54P20A-AZ510
ATSAME54P19A-AZVAO
ATSAME54P20A-AZVAO
ATSAMD51P19A-AU
ATSAMD51P20A-AU
ATSAME54P19A-AU
ATSAME54P20A-AU
ATSAMD51P19A-AU-EFP
ATSAMD51P20A-AU-EFP
ATSAME54P19A-AU-EFP
ATSAME54P20A-AU-EFP
ATSAMD51P19A-AUN01
ATSAMD51P19A-AUT
ATSAMD51P20A-AUT
ATSAME54P19A-AUT
ATSAME54P20A-AUT
ATSAMD51P19A-AUT-EFP
ATSAMD51P20A-AUT-EFP
ATSAME54P19A-AUT-EFP
ATSAME54P20A-AUT-EFP
ATSAME54P20A-AUTEK1
ATSAME54P20A-AFT
ATSAME54P19A-AFT
ATSAMD51P19A-AFT
ATSAMD51P20A-AFT
ATSAME54P20A-AZT
ATSAME54P19A-AZT
ATSAMD51P19A-AZT
ATSAMD51P20A-AZT
ATSAME54P20A-AZT510
ATSAME54P19A-AZTVAO
ATSAME54P20A-AZTVAO